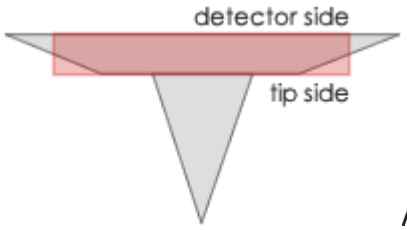
Cantilever Data	Value	Range*
Resonance Frequency	13 kHz	9 - 17 kHz
Force Constant	0.2 N/m	0.07 - 0.4 N/m
Length	450 µm	445 - 455 µm
Mean Width	50 µm	45 - 55 µm
Thickness	2 µm	1.5 - 2.5 µm

NanoWorld® Pointprobe® CONT probes are designed for contact mode imaging. Furthermore this AFM probe can be used for force-distance spectroscopy mode or pulsed force mode (PFM). The CONT type is optimised for high sensitivity due to a low force constant.

All SPM and AFM probes of the Pointprobe® series are made from monolithic silicon which is highly doped to dissipate static charge. They are chemically inert and offer a high mechanical Q-factor for high sensitivity. The AFM tip is shaped like a polygon based pyramid with a typical height of 10 - 15 µm.

Additionally, this AFM probe offers typical AFM tip radius of curvature of less than 8 nm.



A trapezoidal cross section of the AFM cantilever and therefore 30% wider (e.g. NCH) AFM cantilever detector side result in easier and faster laser adjustment. Additionally, because there is simply more space to place and reflect the laser beam, a higher SUM signal is reached.

Tip shape: Standard

Coating: Reflective Aluminum

Aluminum Reflex Coating

The aluminum reflex coating consists of a 30 nm thick aluminum layer

deposited on the detector side of the AFM cantilever which enhances the reflectance of the laser beam by a factor of 2.5. Furthermore it prevents light from interfering within the AFM cantilever.

As the coating is almost stress-free the bending of the AFM cantilever due to stress is less than 2 degrees.

Order Code	Quantity	Data Sheet
CONTR-10	10	yes
CONTR-20	20	yes
CONTR-50	50	no
CONTR-W	380	yes